

Notice of References Cited

Application/Control No.

10/560,001

Applicant(s)/Patent Under
Reexamination
TOMOZAWA ET AL.

Examiner

ALEXANDER C. WITKOWSKI

Art Unit

2853

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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	W	Barzegar: Study of Size (Aspect Ratio) Effect on Longitudinal Piezoelectric Coefficient Measured by Quasistatic Technique, 2002 IEEE Ultrasonics Symposium.			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.